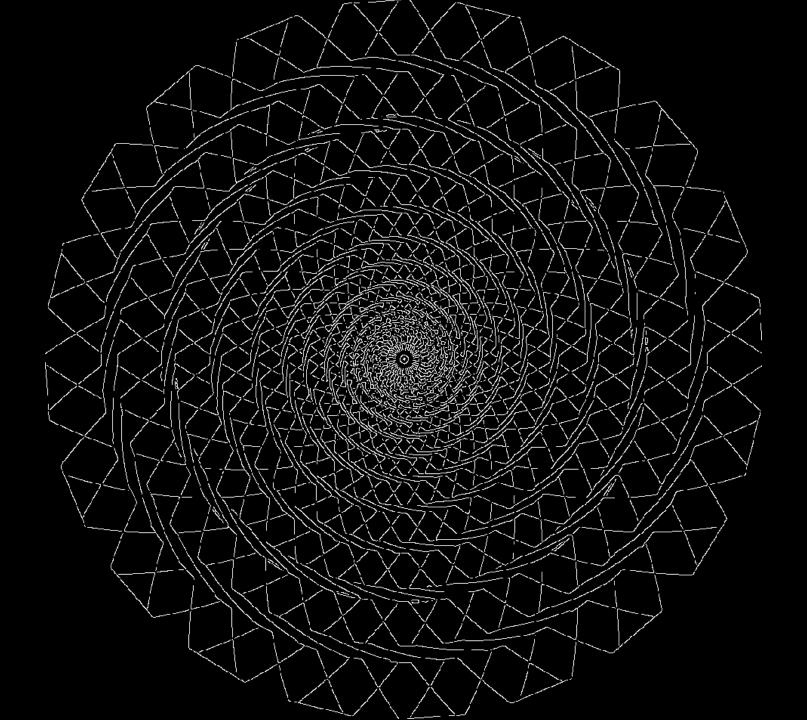
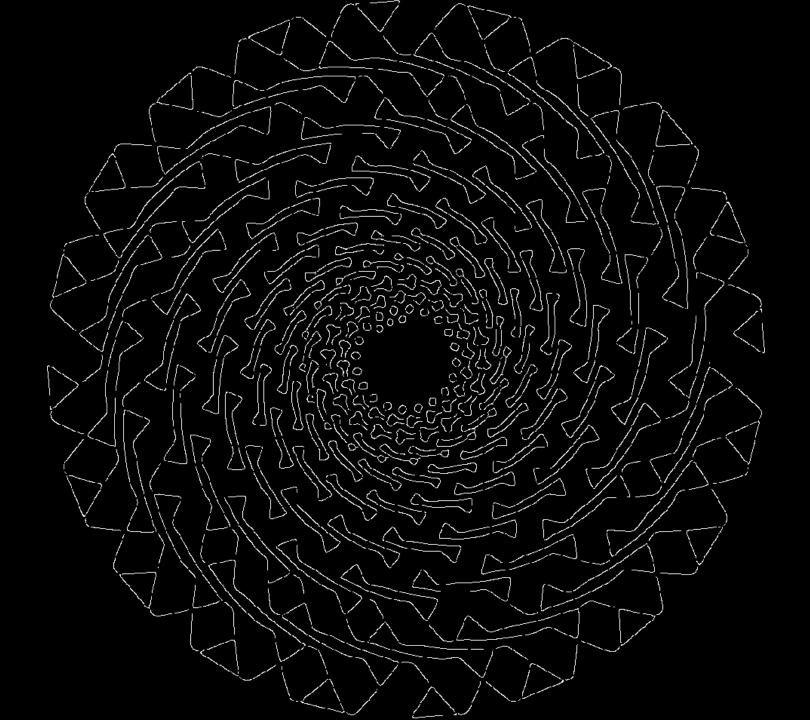
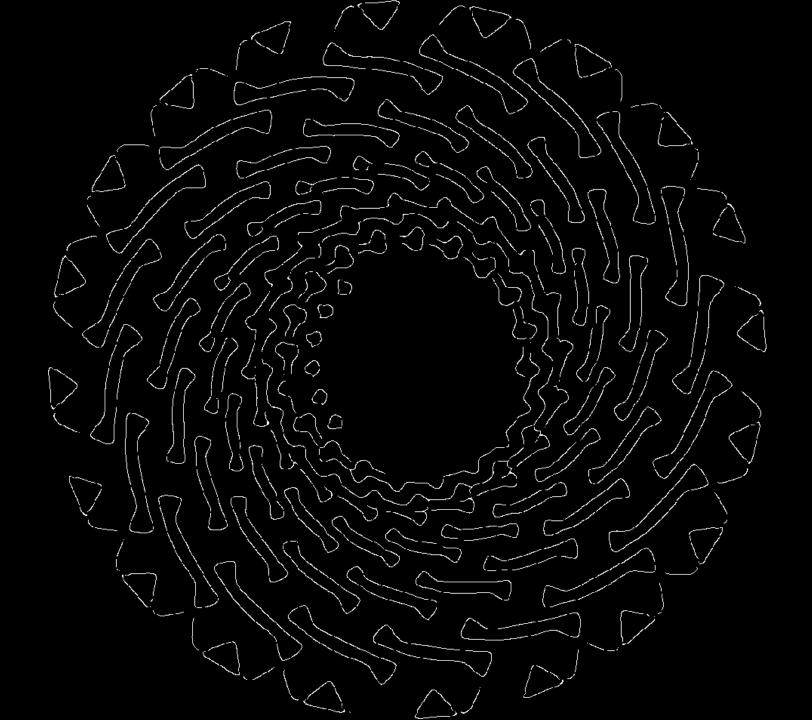
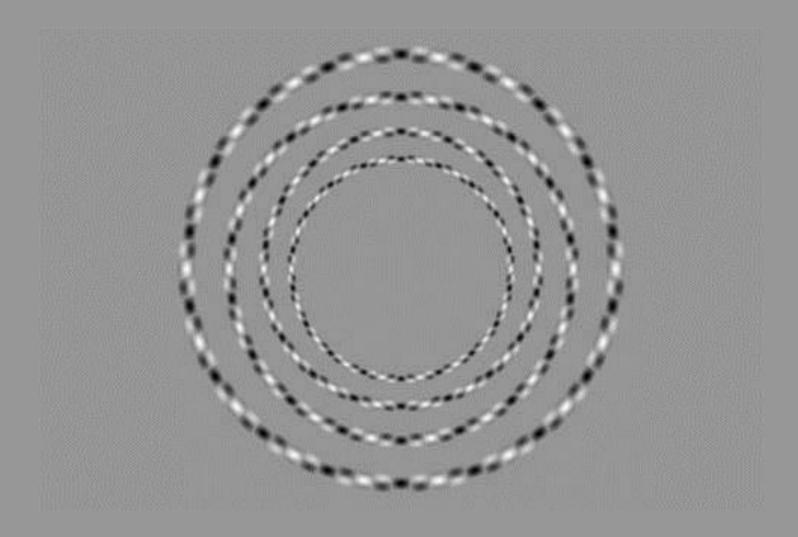


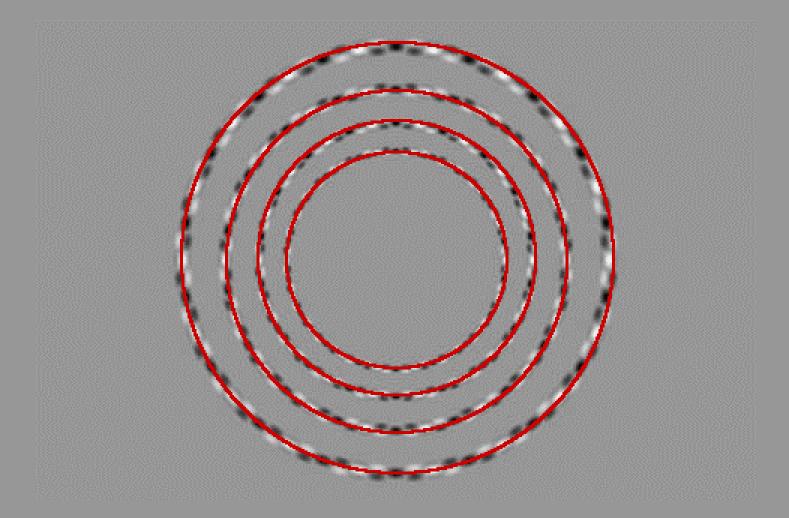
edia - Mysid











# Filtering ----- Edges ----- Corners

# Feature points

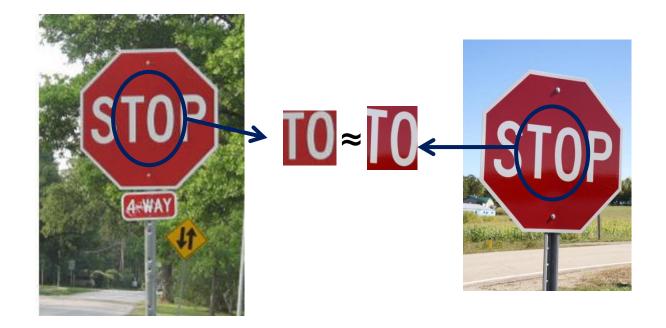
#### Also called interest points, key points, etc. Often described as 'local' features.

#### Szeliski 4.1

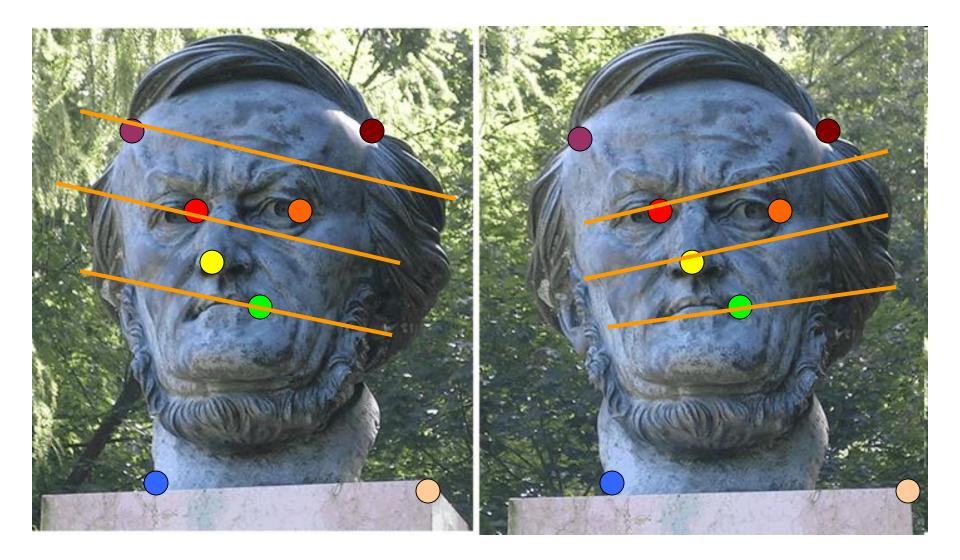
Slides from Rick Szeliski, Svetlana Lazebnik, Derek Hoiem and Grauman&Leibe 2008 AAAI Tutorial

# Correspondence across views

• Correspondence: matching points, patches, edges, or regions across images.



# Example: estimate "fundamental matrix" that corresponds two views



### Example: structure from motion



# **Fundamental to Applications**

- Feature points are used for:
  - Image alignment
  - 3D reconstruction
  - Motion tracking (robots, drones, AR)
  - Indexing and database retrieval
  - Object recognition





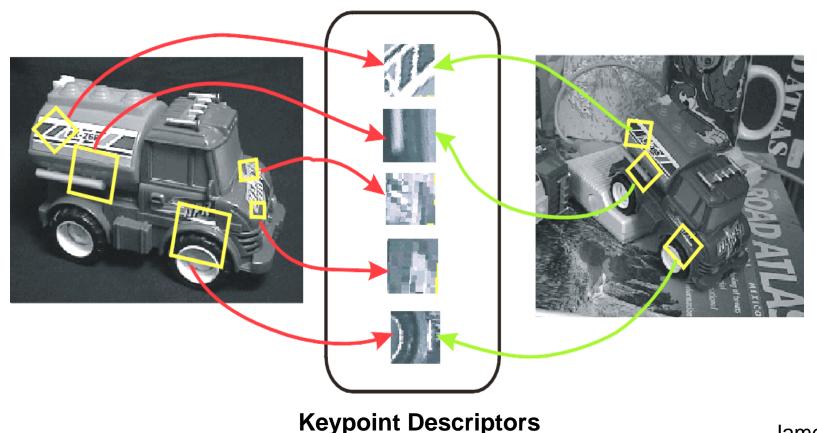


#### **Example: Invariant Local Features**

Detect points that are *repeatable* and *distinctive*.

I.E., invariant to image transformations:

- appearance variation (brightness, illumination)
- geometric variation (translation, rotation, scale).



James Hays

# **Example** application

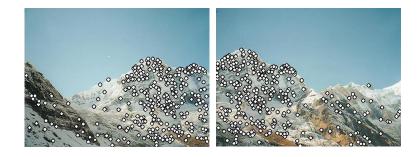
- Panorama stitching
  - We have two images how do we combine them?



# Local features: main components

1) Detection:

Find a set of distinctive key points.



# 2) Description:

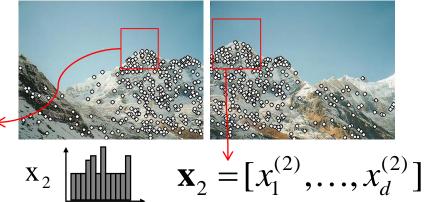
Extract feature descriptor around each interest point as vector.

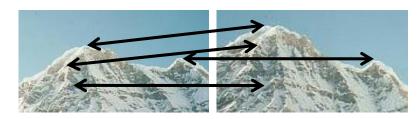
$$\mathbf{x}_1 \quad \mathbf{x}_1 = [x_1^{(1)}, \dots, x_d^{(1)}] \leftarrow$$

# 3) Matching:

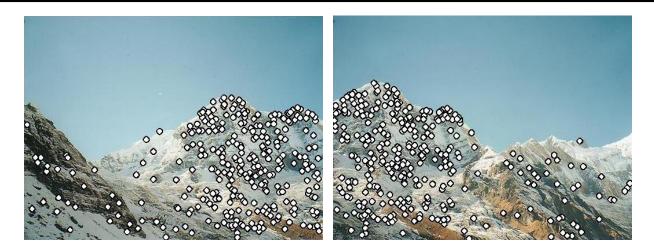
Compute distance between feature vectors to find correspondence.

$$d(\mathbf{x}_1, \mathbf{x}_2) < T$$





# Characteristics of good features



- Repeatability
  - The same feature can be found in several images despite geometric and photometric transformations
- Saliency
  - Each feature is distinctive
- Compactness and efficiency
  - Many fewer features than image pixels
- Locality
  - A feature occupies a relatively small area of the image; robust to clutter and occlusion

# Goal: interest operator repeatability

• We want to detect (at least some of) the same points in both images.

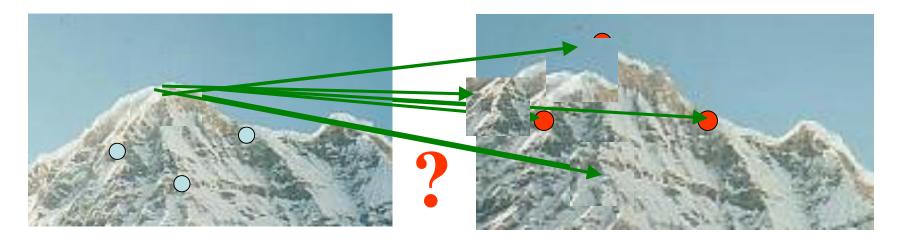


With these points, there's no chance to find true matches!

• Yet we have to be able to run the detection procedure *independently* per image.

# Goal: descriptor distinctiveness

• We want to be able to reliably determine which point goes with which.



• Must provide some invariance to geometric and photometric differences between the two views.

# Local features: main components

### 1) Detection:

Find a set of distinctive key points.



2) Description: Extract feature descriptor around each interest point as vector.

#### 3) Matching:

Compute distance between feature vectors to find correspondence.

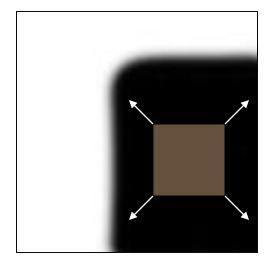
#### **Detection: Basic Idea**

- We do not know which other image locations the feature will end up being matched against.
- But we can compute how stable a location is in appearance with respect to small variations in position *u*.

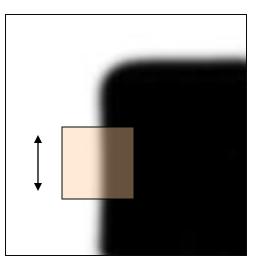
• Compare image patch against local neighbors.

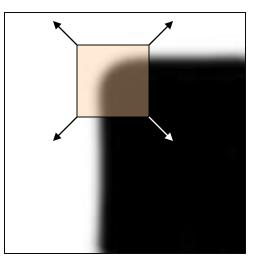
#### **Corner Detection: Basic Idea**

- We might recognize the point by looking through a small window.
- We want a window shift in *any direction* to give *a large change* in intensity.



"Flat" region: no change in all directions

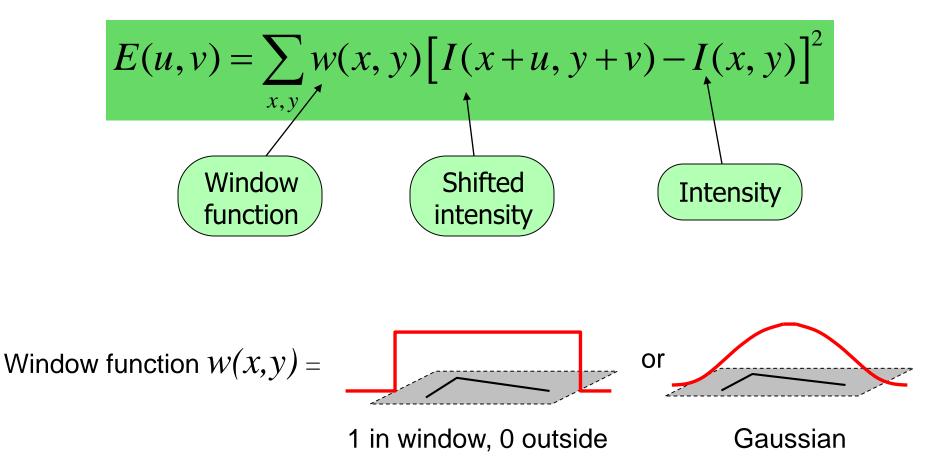




"Edge": no change along the edge direction

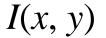
"Corner": significant change in all directions

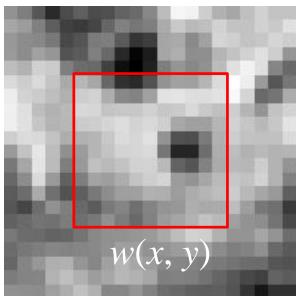
Change in appearance of window w(x,y) for shift [u,v]:

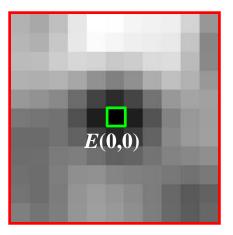


Change in appearance of window w(x,y) for shift [u,v]:

$$E(u,v) = \sum_{x,y} w(x,y) \left[ I(x+u, y+v) - I(x,y) \right]^2$$

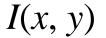


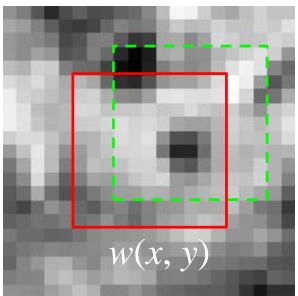


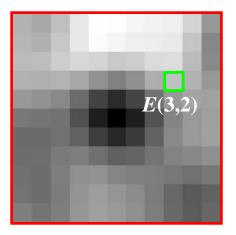


Change in appearance of window w(x,y) for shift [u,v]:

$$E(u,v) = \sum_{x,y} w(x,y) \left[ I(x+u, y+v) - I(x,y) \right]^2$$



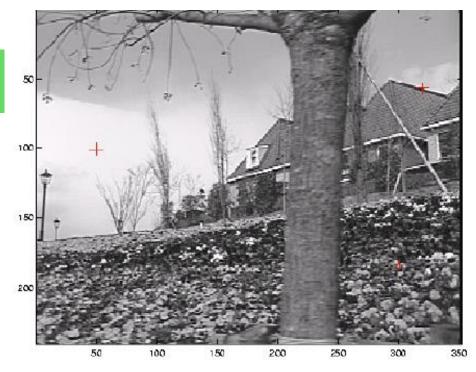


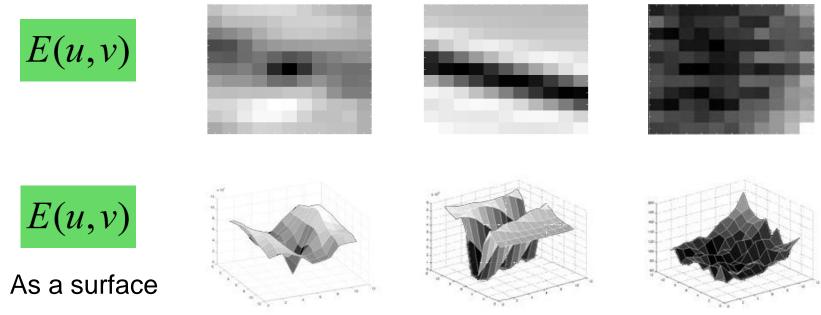


# $E(u,v) = \sum_{x,y} w(x,y) \left[ I(x+u, y+v) - I(x,y) \right]^2$

Think-Pair-Share:

Correspond the three red crosses to (b,c,d).





Change in appearance of window w(x,y) for shift [u,v]:

$$E(u,v) = \sum_{x,y} w(x,y) \left[ I(x+u, y+v) - I(x,y) \right]^{2}$$

We want to discover how E behaves for small shifts

But this is very slow to compute naively. O(window\_width<sup>2</sup> \* shift\_range<sup>2</sup> \* image\_width<sup>2</sup>)

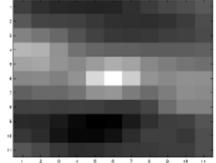
O( $11^2 * 11^2 * 600^2$ ) = 5.2 billion of these 14.6 thousand per pixel in your image

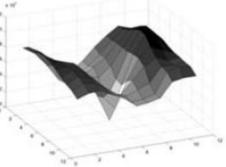
Change in appearance of window w(x,y) for shift [u,v]:

$$E(u,v) = \sum_{x,y} w(x,y) \left[ I(x+u, y+v) - I(x,y) \right]^2$$

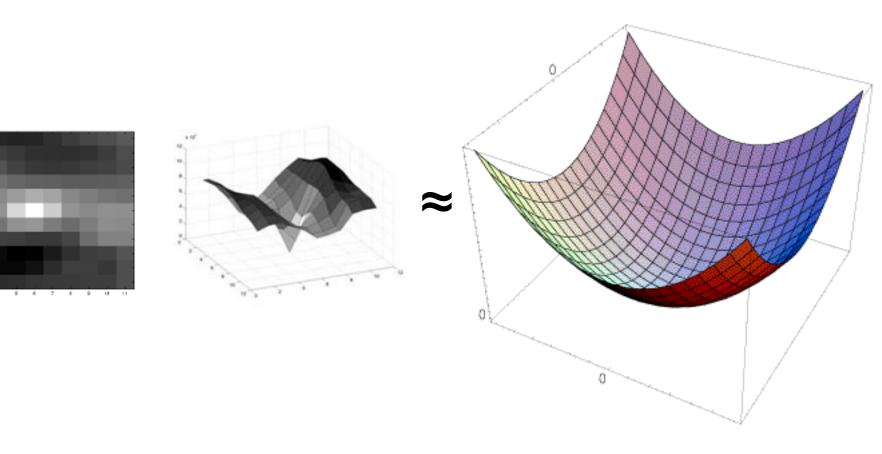
We want to discover how E behaves for small shifts

But we know the response in *E* that we are looking for – strong peak.





# Can we just approximate E(u, v) locally by a quadratic surface?



## Recall: Taylor series expansion

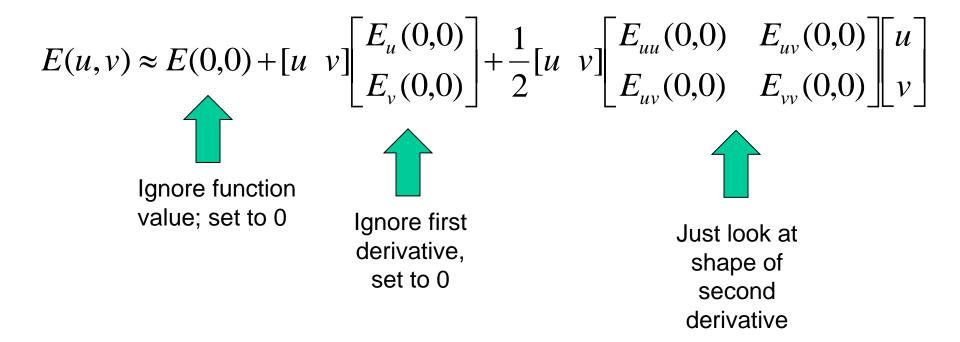
A function f can be represented by an infinite series of its derivatives at a single point *a*:

$$f(a) + \frac{f'(a)}{1!}(x-a) + \frac{f''(a)}{2!}(x-a)^2 + \frac{f'''(a)}{3!}(x-a)^3 + \cdots$$
As we care about window centered, we set  $a = 0$  (MacLaurin series)
$$Approximation of f(x) = e^x centered at f(0)$$

Local quadratic approximation of E(u,v) in the neighborhood of (0,0) is given by the second-order Taylor expansion:

$$E(u,v) \approx E(0,0) + [u \ v] \begin{bmatrix} E_u(0,0) \\ E_v(0,0) \end{bmatrix} + \frac{1}{2} [u \ v] \begin{bmatrix} E_{uu}(0,0) & E_{uv}(0,0) \\ E_{uv}(0,0) & E_{vv}(0,0) \end{bmatrix} \begin{bmatrix} u \\ v \end{bmatrix}$$
  
Notation: partial derivative

Local quadratic approximation of E(u,v) in the neighborhood of (0,0) is given by the second-order Taylor expansion:



# **Corner Detection: Mathematics**

The quadratic approximation simplifies to

$$E(u,v) \approx [u \ v] \begin{bmatrix} E_{uu}(0,0) & E_{uv}(0,0) \\ E_{uv}(0,0) & E_{vv}(0,0) \end{bmatrix} \begin{bmatrix} u \\ v \end{bmatrix} \quad E(u,v) \approx [u \ v] \quad M \qquad \begin{matrix} u \\ v \end{matrix}$$

where *M* is a second moment matrix computed from image derivatives:

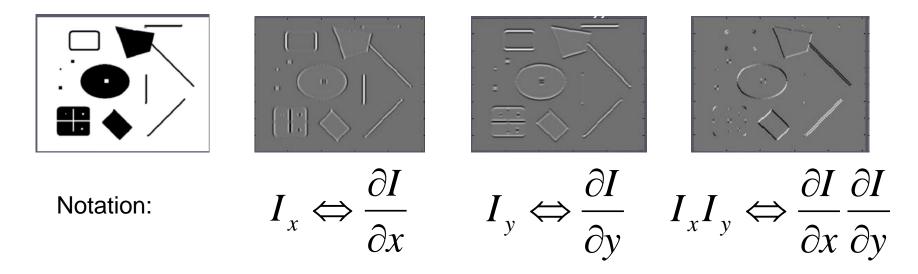
$$M = \sum_{x,y} w(x,y) \begin{bmatrix} I_x^2 & I_x I_y \\ I_x I_y & I_y^2 \end{bmatrix}$$

$$M = \begin{bmatrix} \sum I_x I_x & \sum I_x I_y \\ \sum I_x I_y & \sum I_y I_y \end{bmatrix} = \sum \begin{bmatrix} I_x \\ I_y \end{bmatrix} [I_x I_y] = \sum \nabla I (\nabla I)^T$$

#### **Corners** as distinctive interest points

$$M = \sum w(x, y) \begin{bmatrix} I_x I_x & I_x I_y \\ I_x I_y & I_y I_y \end{bmatrix}$$

#### 2 x 2 matrix of image derivatives (averaged in neighborhood of a point)



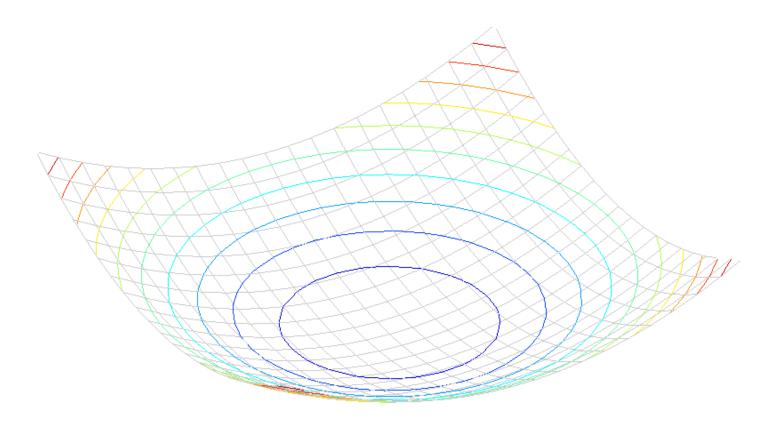
# Interpreting the second moment matrix

The surface E(u, v) is locally approximated by a quadratic form. Let's try to understand its shape.

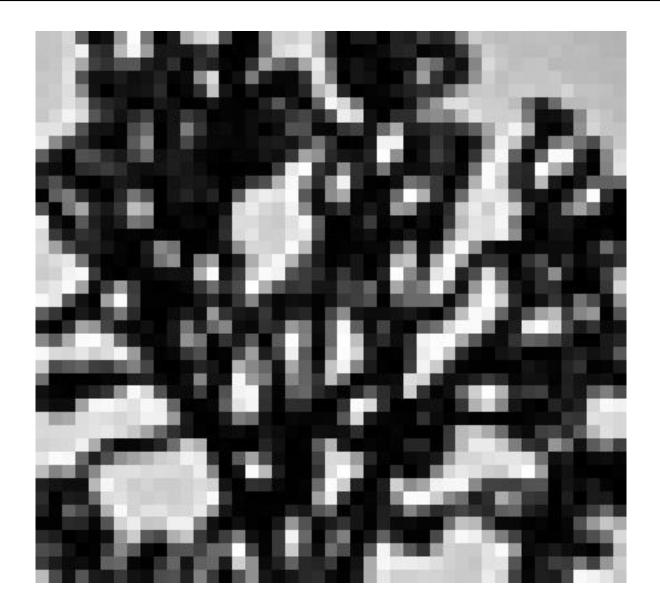
$$E(u,v) \approx [u \ v] \ M \begin{bmatrix} u \\ v \end{bmatrix}$$
$$M = \sum_{x,y} w(x,y) \begin{bmatrix} I_x^2 & I_x I_y \\ I_x I_y & I_y^2 \end{bmatrix}$$

# Interpreting the second moment matrix

Consider a horizontal "slice" of E(u, v):  $\begin{bmatrix} u & v \end{bmatrix} M \begin{bmatrix} u \\ v \end{bmatrix} = \text{const}$ This is the equation of an ellipse.

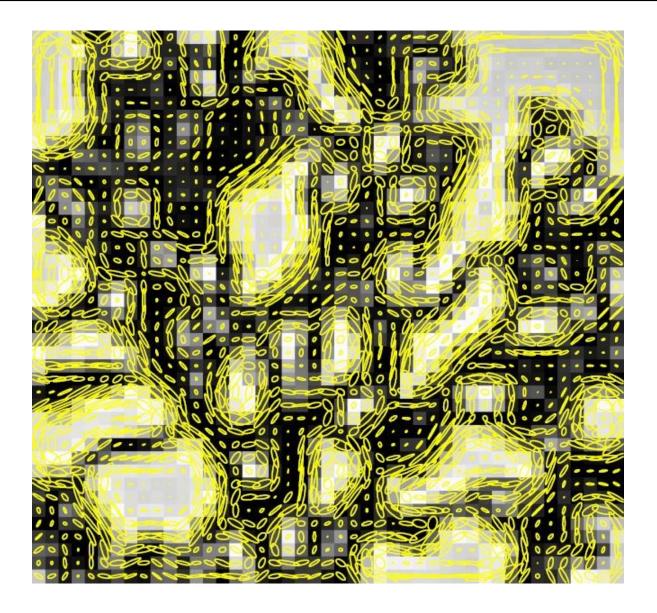


# Visualization of second moment matrices



James Hays

# Visualization of second moment matrices



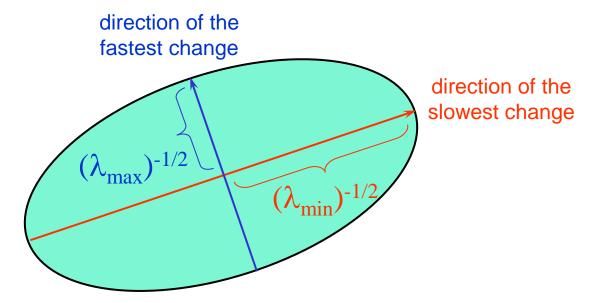
# Interpreting the second moment matrix

Consider a horizontal "slice" of E(u, v):  $\begin{bmatrix} u \\ v \end{bmatrix} = \text{const}$ 

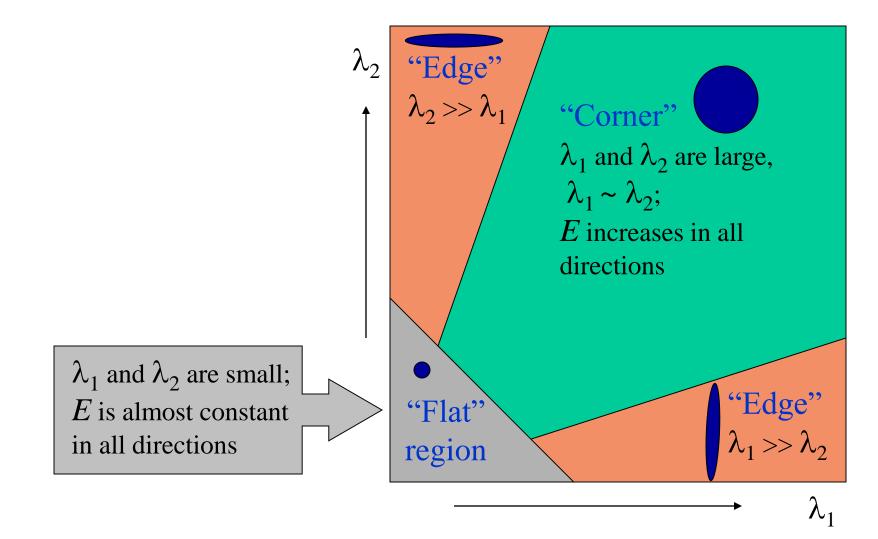
This is the equation of an ellipse.

Diagonalization of M: 
$$M = R^{-1} \begin{bmatrix} \lambda_1 & 0 \\ 0 & \lambda_2 \end{bmatrix} R$$

The axis lengths of the ellipse are determined by the eigenvalues, and the orientation is determined by a rotation matrix R.



#### Classification of image points using eigenvalues of M

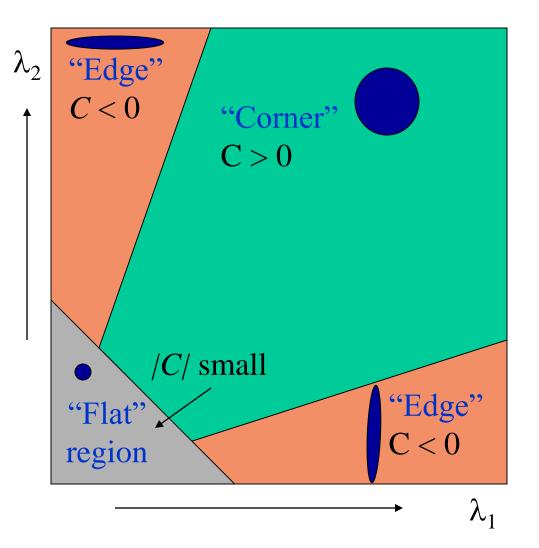


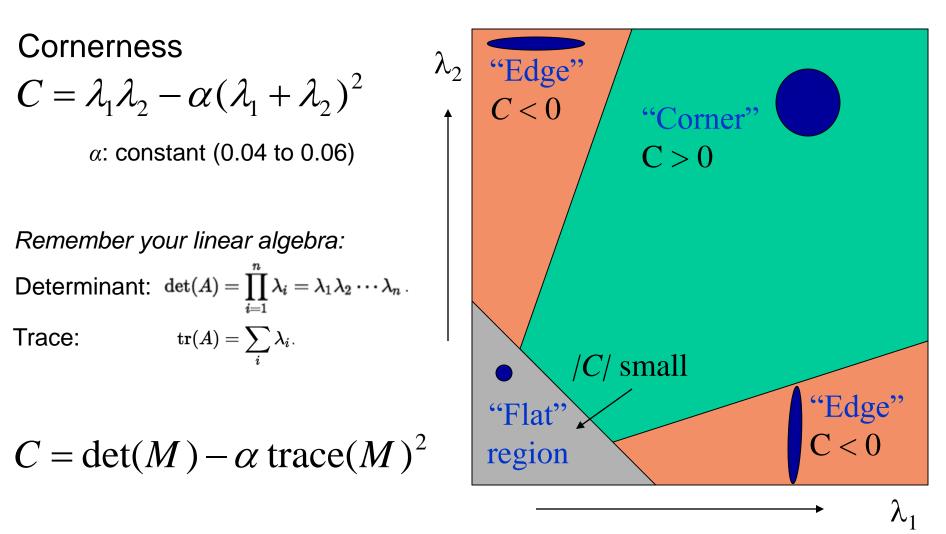
#### Classification of image points using eigenvalues of M

Cornerness

$$C = \lambda_1 \lambda_2 - \alpha (\lambda_1 + \lambda_2)^2$$

*α*: constant (0.04 to 0.06)

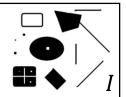




- 1) Compute *M* matrix for each window to recover a *cornerness* score *C*.
  - Note: We can find *M* purely from the per-pixel image derivatives!
- 2) Threshold to find pixels which give large corner response (C > threshold).
- 3) Find the local maxima pixels, i.e., suppress non-maxima.

C.Harris and M.Stephens. <u>"A Combined Corner and Edge Detector."</u> *Proceedings of the 4th Alvey Vision Conference*: pages 147—151, 1988.

# Harris Corner Detector [Harris88]

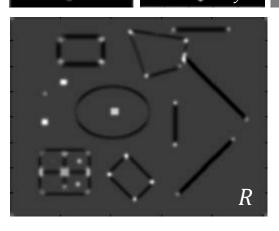




- 0. Input image We want to compute M at each pixel.
- 1. Compute image derivatives (optionally, blur first).



- 2. Compute *M* components as squares of derivatives.
- 3. Gaussian filter g() with width  $\sigma$



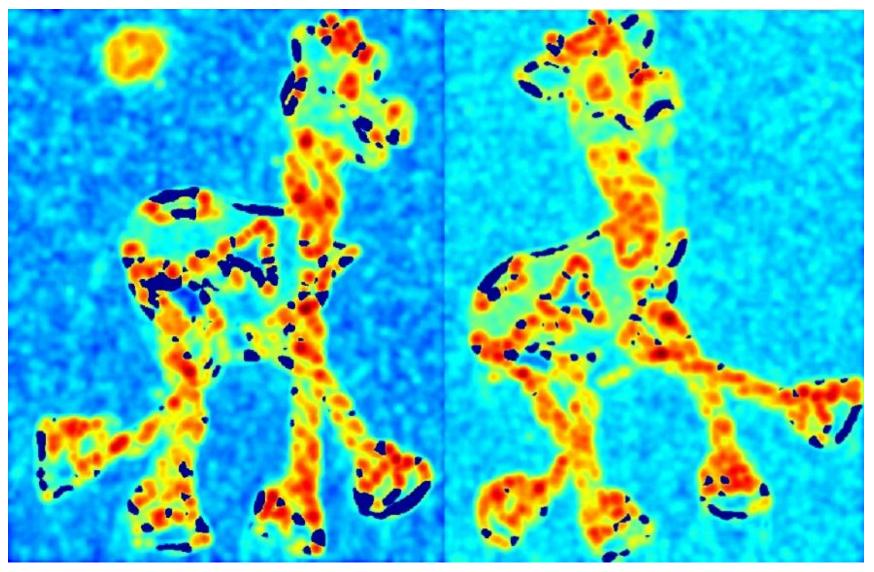
4. Compute cornerness

$$C = \det(M) - \alpha \operatorname{trace}(M)^{2}$$
  
=  $g(I_{x}^{2}) \circ g(I_{y}^{2}) - g(I_{x} \circ I_{y})^{2}$   
 $-\alpha [g(I_{x}^{2}) + g(I_{y}^{2})]^{2}$ 

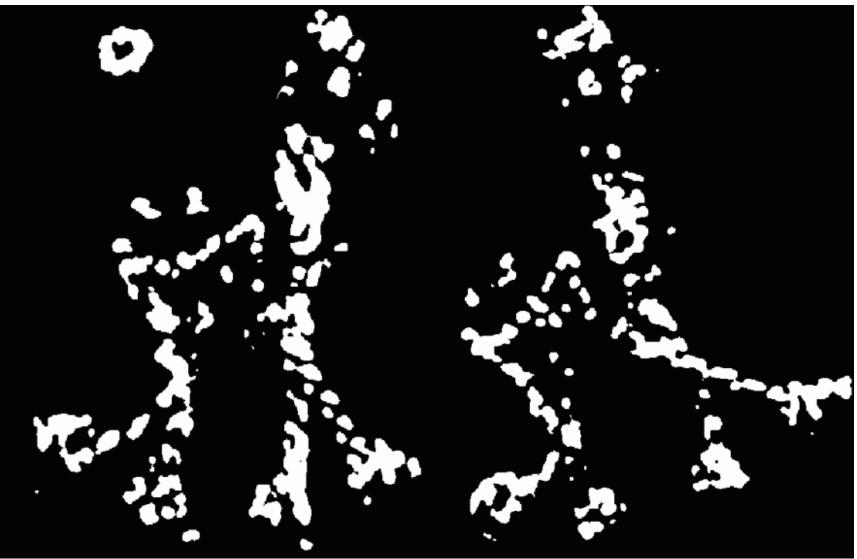
- 5. Threshold on C to pick high cornerness
- 6. Non-maxima suppression to pick peaks.



#### Compute corner response C



#### Find points with large corner response: *C* > threshold



#### Take only the points of local maxima of C

•••

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# Invariance and covariance

Are locations *invariant* to photometric transformations and *covariant* to geometric transformations?

- Invariance: image is transformed and corner locations do not change
- **Covariance:** if we have two transformed versions of the same image, features should be detected in corresponding locations

